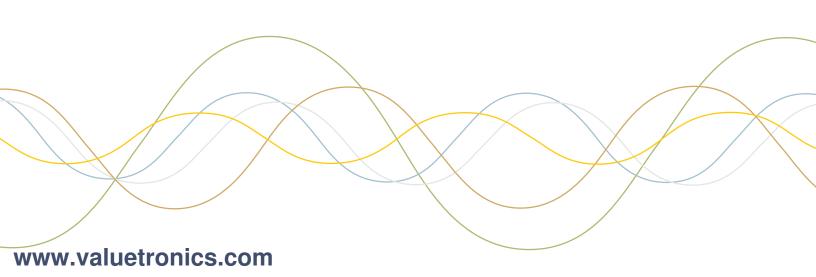


ATS-1

Audio Precision Quality in a Low-Cost, Stand-Alone Test Set

Unmatched Value





The ATS-1 family of audio test instruments—at home on the bench, or in a test rack under GPIB control.

With thousands of units sold, you'll find the ATS-1 family of audio analyzers in operation around the world in maintenance, engineering and production facilities. Whether in broadcast, communications, bench or production use, ATS-1 offers a complete easy-to-use audio test set ready for almost any environment. With twelve different measurement functions selectable at the push of a button, ATS-1 is comprehensive while remaining user-friendly. Its popularity is no less due to its outstanding performance specifications; yet ATS-1 is as affordable as lower-performing test sets.

Analog Only or full Dual Domain—Analog and Digital

System replacement for obsolete equipment:

HP8903B emulation mode over HPIB (GPIB)

Unparalleled Precision

Low Distortion

Analog System THD+N 80 kHz BW **-92 dB**Digital Distortion THD+N ≤**-140 dB**High Analog Bandwidth

Signal Generation to 120 kHz

Low Noise

22 Hz-22 kHz **< -114 dBu**

A-weighted < -118 dBu

Wide Input Voltage Range

Input Range 80 mV-250 V in 10 dB steps

Flat Response

20 Hz-20 kHz ±0.05 dB

Low Crosstalk

Input < -120 dB

Output < -110 dB

Low Jitter

Generator < 0.8 ns

Analyzer < 1.6 ns

The ATS-1 Access

ATS-1 Access includes comprehensive analog generation and measurement, with two outputs and two inputs. Easy-to-set-up sweep capability produces graphs of frequency response, distortion vs. frequency and even amplitude sweeps. Non-volatile storage of up to 30 tests allows easy one-button recall of your favorite test setup. Connect ATS-1 to a compatible printer and produce reports incorporating high-resolution graphs. If you work with digital audio, the ATS-1 Dual Domain® model adds AES3/SPDIF audio and interface measurement capabilities to the comprehensive analog capabilities of the ATS-1 family.

Analog+Digital+AES3/SPDIF: the ATS-1 Dual Domain

ATS-1 Dual Domain® is a comprehensive audio test set for both analog and digital audio, as well as for generation and measurement of AES3/SPDIF digital interface characteristics such as jitter. Like our 2700 Series family of instruments, ATS-1 Dual Domain features true dual domain architecture. Digital signals are generated and measured purely in the digital domain, resulting in the extremely low distortion and noise residuals necessary for making useful digital audio measurements.



www.valuetronics.com

solutions

Performance, Measurement Power, and Ease-of-Use

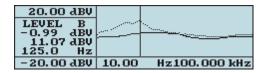
Easy to Use

Measurement functions are simply selected from the front panel. Just press a button

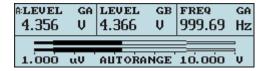


and make the measurement. Selection of analog and digital inputs is clearly indicated on the front panel with LED legends. ATS-1 makes graphs of swept measurements in real time

on the high contrast back-lit LCD display, including both frequency and amplitude sweeps. Hard copy high-resolution graphs,



compact screen-sized graphs or tabular data listings can be made from your ATS-1 to laser or ink jet printers at the touch of a button. *Bargraphs* can display measurements ranging from AC mains power line distortion to digital interface error rate ...and nearly everything in between. Sepa-



rate buttons and knobs provide independent control of frequency and amplitude. The buttons provide large and medium steps (decade and 1/3 octave steps for frequency, 10 dB and 1 dB for amplitude), with knobs for finer resolution. When not otherwise



used, the setting knobs and buttons also provide a convenient human interface for scrolling display cursors and for entry of other settings and data.

Stereo:

ATS-1 Dual Domain is a true two channel instrument. Both analog and digital level functions measure both inputs simultaneously. Phase and level ratio measurements are also available.

Full Range of Analog & Digital Testing Facilities:

ATS-1 Dual Domain provides complete and parallel measurement capabilities for both analog and digital audio signals. Measurements common to both domains include: Amplitude, Noise, Level (2 channels simultaneously), Frequency, Phase, THD+N, SMPTE/DIN, IMD, Crosstalk and Level Ratio. Standard A-weighting, CCIR 468, and LP/HP filters are included in both domains. RMS and quasi-peak (CCIR 468) detectors are available in both domains.

Analog Performance:

The low distortion transformer-coupled analog generator supplies a full +30.17 dBu (+29.5 dBm into 600 Ω) at selectable (50 Ω , 150 Ω or 600 Ω) source impedances. Extremely low analyzer noise and residual distortion support measurement of high performance digital devices.

Analog Convenience Functions:

In addition to the above measurements, the analog *GEN LOAD* function measures the input resistance of your device at any frequency you choose and makes swept impedance measurements (including loudspeakers).

AC MAINS CHECK measures the voltage, frequency and distortion of the power line without hazardous direct connections.

BARGRAPH display in AC MAINS CHECK function provides a visible history of maximum and minimum mains voltage excursions.

aac mains 117.0 V		z.	FREQ 59.987	Hz
A:GEN:SINE	1.000	V	1.000	kHz
SELF TEST				

The dBg unit (dB referred to the present analog generator amplitude) is useful for compression threshold measurements or rapid response sweeps at several different absolute levels, as well as for input to output gain/loss measurements.

600 Ω Analog Input Terminations are individually switchable for each channel of the analog analyzer.

Turn on ATS-1: Audio Testing to Meet Your Challenges

Comprehensive Analog and **Digital Functions**

Digital Performance:

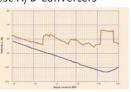
ATS-1 Dual Domain uses a true DSP-implemented analyzer for digital measurements, which results in -130 dB residual THD+N, 0.01 dB flatness, and -140 dBFS residual noise. Other mixed-signal test sets in the



same price range have no digital analyzer, but use a D/A converter and an analog analyzer. These architectures "bottom out" at -70 dB to -84 dB residual THD+N (12-14 bit effective performance), and 0.1 dB flatness. With today's best A/D converters

measuring -108 to -112 dB THD+N, their real performance is invisible to these mixed signal analyzers

...buried under the distortion floor.



A competitive instrument lacking a DSP analyzer produces false THD+N readings (red trace) from a popular A/D converter; but both the ATS-1 Dual Domain and the Audio Precision 2700 Series graph the analyzer's noise and true performance of the converter (from 5 dB to 28 dB lower), as shown by the blue trace.

Separate & Independent Analog & Digital **Generators:**

Often necessary for dual domain testing. You may, for example, drive the inputs of an A/D converter with the low-distortion analog sine while simultaneously driving the converter's digital reference (house sync) input with the digital generator. Then, add jitter or vary the sample rate to see the effect on THD+N, IMD, or noise. Competitive units can drive only one domain at a time or use their analog generator to create the digital jitter, and thus can't make this measurement at all.

Separate Digital Inputs & Outputs:



Three I/O formats: XLR, BNC, and optical (Toslink®). All are completely separate from the analog audio XLR connectors, permitting both digital and analog generators to operate simultaneously. No cable changes required to go from A/D to D/A to D/D to A/A testing of a digital tape machine, for example.

Digital & Analog Monitors:

Listen to all measurements in the digital

and analog domains over the internal loudspeaker or a pair of head-



phones. In the analog domain, monitor signals or distortion. In the digital domain, the incoming signal, distortion, or jitter can all be monitored.

Jitter Meter:

ATS-1 Dual Domain includes jitter measurement in nanoseconds or in Unit Intervals. Two filter selections are provided for the

0.484 UI	4.99 Vpp	400.46 Hz
D:GEN:SINE	1.0000 Ffs	997.00 Hz
UN-WTD	HP: 50 Hz	RMS

jitter meter: a 700 Hz high-pass filter used for residual jitter measurements according to AES standards, and a 50 Hz high-pass filter for jitter response measurements.

Other Interface Signal Measurements:

ATS-1 Dual Domain measures key digital I/O interface parameters in addition to jitter, including sample rate, AES signal voltage, frame delay through the device under test, and delay of the input signal relative to a house sync reference (frame or block).

D:RATE G 48000.0 Hz	xlr loz g 2.98 Vpp	DELAY G 24.30 ns
D:GEN:SINE	1.0000 F ^f 5	$1.0000\mathrm{kHz}$
REF: STAT	INP:24bit	OUT BLOCK

Flexible Interface Impairment Simulation:

Flexible digital interface testing is vital for troubleshooting and verifying performance of digital audio at the systems level. ATS-1 Dual Domain allows simulation of real world transmission and interface problems.



Vary the digital output signal to test the acceptance range of your digital devices. Set sample rate anywhere from 28.8 kHz to 99.9999 kHz, not just at the three standard frequencies. Inject jitter amplitude from 0 UI to 2.5 UI (415 ns at 48 kHz) in 0.01 UI (1.6 ns) steps, or 0 UI to 25.5 UI (4150 ns) in 0.1 UI (16 ns) steps.

challenges

Injected jitter frequency can be set from 10 Hz to 38.8 kHz, not just to a fixed frequency. Adjust output signal amplitude continuously from zero to 5.12 Volts in 5 mV increments, not just at a few steps.

Independent Interface I/O Word Lengths:

Word length (resolution) of digital input and output are independently set from 16 to 24 bits. Output resolution is set to match the device under test to assure proper dither. Input resolution must be set to exclude signal in the AUX bits or other low-level bit activity meaningless to the desired measurement.

D:RATE	BNC HiZ	DELAY
48000.0 Hz	0.69 Vpp	260.72 UI
D:GEN:SINE	-60.00 dBfs	$1.0001~\mathrm{kHz}$
REF: MEAS	INP:24bit	OUT BLOCK

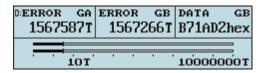
Independent Input & Output Sample Rates:

Lets you test sample rate converters. Measurement of the incoming embedded audio signal can be referred to the incoming sample rate, status byte indication of rate, or the outgoing generator rate.

D:SEND: CONS	EMPH: NONE	SR: 32 kHz
D:INP:CONS	EMPH: NONE	SR: 32kHz
COPY: NO		NO ERRORS
COPY: NO		VALID

Data ✓ Error Testing Capability for Digital Audio Signals:

Stimulate the test device with random data and display current or totaled error measurements on both channels. The signal and



analysis techniques are compatible with the BITTEST feature of our System products, so you can test a transmission link end-to-end with an ATS-1 Dual Domain at one end and a System Two, Cascade or 2700 Series dual domain instrument at the other.

Other Digital Convenience Functions:

Digital Status bytes are displayed and set in high-level English.

D:ERROR	GA	ERROR	GB	DATA GA
	0		0	6FEA40hex
24	16	88	111	ACTIVEBIT
D:ERROR	GA	ERROR	GB	DATA GA
	_		_	E A A R C A R
	U		U	5A0D60hex
	U		U	БАОЛРОНЕХ
24	U 16		U	астиацвіт

Error flag displays for confidence, lock, coding, parity errors and the validity bit are included.

Additional active bit and actual bit displays on the panel help determine the word length of the incoming signal and detect stuck bits.

Digital Dither:

ATS-1 Dual Domain includes a full complement of dither selections—triangular and rectangular probability distribution functions; white or shaped spectrum.

Dither amplitude is automatically set to the proper value for the output word length and the selected probability function.

Sample & Frame Sync:

Synchronize ATS-1 Dual Domain sample and frame sync to the digital reference (house sync) input.

Digital Pass Mode:

Sends the input digital audio content to the output while modifying status bytes, validity bit, etc. ATS-1 Dual Domain can thus be used as a problem-solver between incompatible equipment.

Signal Monitoring Outputs:

A digital signal appropriate for syncing an external oscilloscope may be derived from the input sample rate, output sample rate, input block rate, output block rate, digital audio waveform, jitter signal, or the detected interface errors. A buffered version of the balanced AES3 signal from the XLR input is also available, which coupled with the high input impedance of the XLR in bridging mode allows non-intrusive digital line measurements with conventional ground-referenced oscilloscopes.

Connectivity, Test Results and GPIB or HPIB Automation

Versatile Connectivity

Choose among three different analog connector panels for your ATS-1. The connector panel can be mounted on the front of your instrument for convenience, or on the rear of the instrument if you'd prefer your ATS-1



hard-wired in a rack. All the panels come with extra dual banana and ground lugs. The XLR panel allows for either balanced or unbalanced measurements by using a simple dual banana-to-BNC (or to RCA phono) adapter.

Save & Recall Tests:

Save 30 instrument setups, including sweep results data, time-stamped from the internal clock calendar. Use for



repeatable, easy bench and production testing or when in the field, for storing test

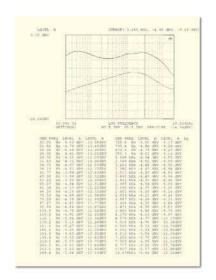
SAVE	CANCEL	SCROLL UP
15 ATHP+	N_ZPAMPL	971017 00:22 971017 00:22
16 XTALK Ly empty	рата	971017 00:22
18	/#FREQ	7251112 17:50
23 03111211	A:FREQ	951112 17:50
RECALL	PAGE	SCROLL DN

data to be printed or analyzed later. Each saved test includes all settings for the entire instrument, a default description or your own title for the test, the date and time, and the last test sweep result data.



Print Graphs And Test Results:

ATS-1 prints graphs, panel setups and measured data either to laser (PCL compatible) or inkjet printers. Front panel keys select two sizes of graph output (including cursor data), tabular sweep data, bargraphs and front panels for printing.



IEEE-488.2 GPIB Port:

An IEEE-488.2 GPIB interface port is included on the ATS-1. The commands closely model the front panel interface to make software development more productive. ATS-1 provides full query back of all manual set-

tings and on-line help to speed up code development. Measurement sweep data is stored in the instrument for quick batch transfers without holding up GPIB bus traffic.

Settled GPIB Readings:

Reliable measurements are assured by algorithms inside the instrument which automatically compensate for varying device settling speeds. Settling can be disabled for measurements of jitter or other instantaneous values.

GPIB Software Drivers

Audio Precision supports the ATS-1 with a National Instruments LabView and LabWindows CVI driver for C and Basic programmers. The LabWindows driver runs with National Instruments GPIB interface cards for personal computers. The driver speeds development of test routines by eliminating the need to learn the ATS-1 programming mnemonics.

HP8903B GPIB Emulation Mode

GPIB ADDR 31	CMD MODE HPIB	FREQ STEP
I DLE LOC	ERRM PON	AMPL STEP
Loc	*STB OO h	1dB/ISO

ATS-1 also emulates the HP8903B audio analyzer HP command set for a simple replacement of slow and outdated equipment in existing systems. A front panel button selects between the Audio Precision 488.2 (GPIB) command mode and the HPIB command mode.

Low Distortion Sine Wave	40.11.4.400.111	
Frequency Rango		
Frequency Range Frequency Accuracy	10 Hz to 120 kHz ±0.5 %	
Amplitude Range Balanced	(20 Hz to 30 kHz) <0.25 mV to 26.25 Vrms [-70 dBu to	
Unbalanced	+30.6 dBu] <0.25 mV to 13.12 Vrms [-70 dBu to +24.6 dBu]	SMPTE (DIN) I Test Signal Com
Amplitude Accuracy	±0.2 dB [±2.3 %] at 1 kHz	IMD Measured
Amplitude Resolution Flatness (1 kHz ref)	0.01 dB	
10 Hz-20 kHz Residual THD+N	±0.05 dB	Measurement R Accuracy
25 Hz-20 kHz	\leq (0.0025% + 3 μ V), 80 kHz BW [-92 dB]	Residual IMD
Square Wave	2011 20111	Residual IND
Frequency Range Amplitude Range	20 Hz-30 kHz	Wow & Flutter
Balanced Unbalanced	0.71 mVpp to 34.73 Vpp 0.71 mVpp to 17.36 Vpp	Test Signal Com Accuracy (4 Hz)
Amplitude Accuracy	±0.3 dB [±3.5 %] at 400 Hz	Detection Mode Residual W+F
Rise/fall time	Typically 2.5–3.0 μs	Residual W+F
SMPTE (or DIN) Test Signals w LF Tone	50, 60, 70, or 250; all ±1.0 %	DIGITAL SIGN
HF Tone Range	7 kHz or 8 kHz (±1 %)	DIGITAL OUTPL
Mix Ratio Residual IMD	4:1 (LF:HF) 0.0015 % [-96.5 dB], 60 Hz + 7 kHz	Output Formats
AUTRUT CHARACTERICTICS	or 250 Hz + 8 kHz	Sample Rates
OUTPUT CHARACTERISTICS Source Configuration	Selectable balanced or unbalanced	Sample Rate Ac
Source Impedances		Word Length
Balanced	50 Ω (±2 Ω), 150 Ω (±2 Ω), or 600 Ω (±6 Ω)	Sine Wave
Unbalanced Output Current Limit	50 Ω (±2 Ω)	Frequency Rang
Output Current Limit Max Output Power	75 mA peak	Frequency Reso
Balanced Unbalanced	+29.9 dBm into 600 Ω (Rs = 50 Ω) +23.8 dBm into 600 Ω (Rs = 50 Ω)	Flatness
Output Related Crosstalk	≤-110 dB or 10 µV, whichever is	Residual Distort
(10 Hz-20 kHz)	greater	Square Wave
ANALOG ANALYZER		Frequency Rang Frequencies ava
ANALOG INPUT CHARACTERIST		CMDTE/DIN IMI
Input Ranges Maximum Rated Input	80 mV to 250 V in 10 dB steps 350 Vpk, 140 Vrms (dc to 20 kHz);	Upper Tone Ran
Input Impedance	overload protected	Lower Tone Ran
Balanced (each side) Unbalanced	Nominally 100 k Ω // 150-200 pF Nominally 100 k Ω // 150-200 pF	Amplitude Ration Residual Distort
Terminations	Selectable 600 Ω ±1 %	Random Gener
CMRR 80 mV–2.5 V range Input Related Crosstalk	≥70 dB, 50 Hz-20 kHz ≤-120 dB or 1 µV, whichever is	Waveform
10 Hz-20 kHz	greater	Dither (all way
Wideband Amplitude/Noise Fu		Probability Dist
Measurement Range	<1 µVrms to 140 Vrms [-118 dBu to +45 dBu]	Spectral Distrib
Accuracy (1 kHz) Flatness (1 kHz ref)	±0.2 dB [±2.37 %] unweighted	
Bandwidth Limiting Filters	±0.05 dB (20 Hz-20 kHz)	Amplitude
LF –3 dB HF –3 dB	<10 Hz; 400 Hz ±5 % (3-pole) 22 kHz; 30 kHz; 80 kHz (3-pole), or	AES/EBU INTI
Woighting Filtors	300 kHz	Amplitude Rand
Weighting Filters	ANSI-IEC "A"; CCIR-QPK; CCIR-ARM; CCIR-RMS	Balanced (XĽ
Optional Filters Detection	Up to 2 (Aux 1 and Aux 2) RMS (<i>i</i> =60 ms); AVG; QPK (CCIR	Unbalanced (Channel Status
	Rec 468)	
Residual Noise 22 Hz–22 kHz BW	≤1.5 µV [-114 dBu]	Validity Flag AES/EBU Impa
A-weighted CCIR-QPK	≤1.5 µV [-114 dBu] ≤1.0 µV [-118 dBu] ≤5.0 µV [-104 dBu]	Induced Jitter
Frequency Meter Related (bot		Jitter Freq Rang
Measurement Range	10 Hz-200 kHz	Jitter Amplitud
<u> </u>	±0.01 % [±100 PPM] 5 digits	
Accuracy	- ang. ac	Residual Jitter
Accuracy Resolution		
Accuracy Resolution Phase Measurement Related Measurement Ranges	±180, +90/-270, or -90/+270 deg	RMS response Peak respons
Accuracy Resolution Phase Measurement Related Measurement Ranges Accuracy 20 Hz–20 kHz	±2.0 deg	RMS response Peak respons Spurious Jitter
Accuracy Resolution Phase Measurement Related Measurement Ranges Accuracy 20 Hz–20 kHz Resolution	±2.0 deg 0.1 deg	RMS response Peak respons Spurious Jitter Jitter & Ref I Jitter On
Accuracy Resolution Phase Measurement Related Measurement Ranges Accuracy 20 Hz–20 kHz Resolution Level Meter Related (both cha	±2.0 deg 0.1 deg nnels)	RMS response Peak respons Spurious Jitter Jitter & Ref I Jitter On REFERENCE INF
Accuracy Resolution Phase Measurement Related Measurement Ranges Accuracy 20 Hz–20 kHz Resolution Level Meter Related (both cha	±2.0 deg 0.1 deg nnels) 10 mV to 140 V for specified accuracy and flatness, useable to <100 µV [-38 dBu to + 45 dBu]	RMS response Peak respons Spurious Jitter Jitter & Ref I Jitter On REFERENCE INF Input Formats
Accuracy Resolution Phase Measurement Related Measurement Ranges Accuracy 20 Hz-20 kHz Resolution Level Meter Related (both cha Measurement Range Accuracy (1 kHz)	±2.0 deg 0.1 deq mnels) 10 mV to 140 V for specified accuracy and flatness, useable to <100 µV [-38 dBu to +45 dBu] ±0.1 dB + 100 µV	RMS response Peak respons Spurious Jitter Jitter & Ref I Jitter On REFERENCE INF Input Formats
Accuracy Resolution Phase Measurement Related Measurement Ranges Accuracy 20 Hz-20 kHz Resolution Level Meter Related (both cha Measurement Range Accuracy (1 kHz)	±2.0 deg 0.1 deg nnels) 10 mV to 140 V for specified accuracy and flatness, useable to <100 µV [-38 dBu to + 45 dBu]	RMS response Peak respons Spurious Jitter Jitter & Ref I Jitter On REFERENCE INF Input Formats Input Sample R Lock Range
Accuracy Resolution Phase Measurement Related Measurement Ranges Accuracy 20 Hz-20 kHz Resolution Level Meter Related (both cha Measurement Range Accuracy (1 kHz) Flatness (1 kHz ref) Bandpass Amplitude Function	±2.0 deg 0.1 deq Innels) 10 mV to 140 V for specified accuracy and flatness, useable to <100 µV [-38 dBu to + 45 dBu] ±0.1 dB + 100 µV (Vin >10 mV) ±0.05 dB (20 Hz-20 kHz)	RMS response Peak respons Spurious Jitter Jitter & Ref Jitter On REFERENCE INF Input Formats Input Sample R Lock Range DIGITAL ANA
Accuracy Resolution Phase Measurement Related Measurement Ranges Accuracy 20 Hz-20 kHz Resolution Level Meter Related (both cha Measurement Range Accuracy (1 kHz) Flatness (1 kHz ref) Bandpass Amplitude Function Tuning Range (f _o)	±2.0 deg 0.1 deq mnels) 10 mV to 140 V for specified accuracy and flatness, useable to <100 µV [-38 dBu to + 45 dBu] ±0.1 dB + 100 µV (Vin >10 mV) ±0.05 dB (20 Hz-20 kHz) 20 Hz to 120 kHz	RMS response Peak respons Spurious Jitter Jitter & Ref Jitter On REFERENCE INF Input Formats Input Sample R Lock Range DIGITAL ANA
Accuracy Resolution Phase Measurement Related Measurement Ranges Accuracy 20 Hz-20 kHz Resolution Level Meter Related (both cha Measurement Range Accuracy (1 kHz) Flatness (1 kHz ref) Bandpass Amplitude Function Tuning Range (f _o) Bandpass Response	±2.0 deg 0.1 deq Innels) 10 mV to 140 V for specified accuracy and flatness, useable to <100 µV [-38 dBu to + 45 dBu] ±0.1 dB + 100 µV (Vin >10 mV) ±0.05 dB (20 Hz-20 kHz)	RMS respons Peak respons Spurious Jitter Jitter & Ref Jitter On REFERENCE INI Input Formats Input Sample R Lock Range DIGITAL ANA DIGITAL INPUT Input Formats Sample Rates
Accuracy Resolution Phase Measurement Related Measurement Ranges Accuracy 20 Hz-20 kHz Resolution Level Meter Related (both cha Measurement Range Accuracy (1 kHz) Flatness (1 kHz ref) Bandpass Amplitude Function Tuning Range (f _o) Bandpass Response Accuracy (at f _o) THD+N / SINAD Function	±2.0 deg 0.1 deq mnels) 10 mV to 140 V for specified accuracy and flatness, useable to <100 µV [-38 dBu to + 45 dBu] ±0.1 dB + 100 µV (Vin >10 mV) ±0.05 dB (20 Hz-20 kHz) 20 Hz to 120 kHz Q=5 (2-pole) ±0.3 dB, 20 Hz-120 kHz	RMS response Peak respons Spurious Jitter Jitter & Ref Jitter On REFERENCE INF Input Formats Input Sample R Lock Range DIGITAL ANAL DIGITAL INPUT Input Formats Sample Rates Word Length
Accuracy Resolution Phase Measurement Related Measurement Ranges Accuracy 20 Hz-20 kHz Resolution Level Meter Related (both cha Measurement Range Accuracy (1 kHz) Flatness (1 kHz ref) Bandpass Amplitude Function Tuning Range (f _o) Bandpass Response Accuracy (at f _o) THD+N / SINAD Function Fundamental Range	±2.0 deg 0.1 deq mnels) 10 mV to 140 V for specified accuracy and flatness, useable to <100 µV [-38 dBu to + 45 dBu] ±0.1 dB + 100 µV (Vin >10 mV) ±0.05 dB (20 Hz-20 kHz) 20 Hz to 120 kHz Q=5 (2-pole) ±0.3 dB, 20 Hz-120 kHz	RMS response Peak respons Spurious Jitter Jitter & Ref Jitter On REFERENCE INF Input Formats Input Sample R Lock Range DIGITAL INPUT Input Formats Sample Rates Word Length EMBEDDED AUI
Accuracy Resolution Phase Measurement Related Measurement Ranges Accuracy 20 Hz-20 kHz Resolution Level Meter Related (both cha Measurement Range Accuracy (1 kHz) Flatness (1 kHz ref) Bandpass Amplitude Function Tuning Range (f _o) Bandpass Response Accuracy (at f _o) THD+N / SINAD Function Fundamental Range Measurement Range	±2.0 deg 0.1 deq nmels) 10 mV to 140 V for specified accuracy and flatness, useable to <100 μV [-38 dBu to +45 dBu] ±0.1 dB + 100 μV (Vin >10 mV) ±0.05 dB (20 Hz-20 kHz) 20 Hz to 120 kHz 20 Hz to 120 kHz 0=5 (2-pole) ±0.3 dB, 20 Hz-120 kHz 10 Hz to 100 kHz, THD+N mode .001 %-100 % 400 Hz-1 kHz	RMS response Peak respons Spurious Jitter Jitter & Ref Jitter On REFERENCE INF Input Formats Input Sample R Lock Range DIGITAL INPUT Input Formats Sample Rates Word Length EMBEDDED AUI
Accuracy Resolution Phase Measurement Related Measurement Ranges Accuracy 20 Hz-20 kHz Resolution Level Meter Related (both cha Measurement Range Accuracy (1 kHz) Flatness (1 kHz ref) Bandpass Amplitude Function Tuning Range (f _o) Bandpass Response Accuracy (at f _o) THD+N / SINAD Function Fundamental Range Measurement Range Measurement Range SINAD Range Accuracy	±2.0 deg 0.1 deq mnels) 10 mV to 140 V for specified accuracy and flatness, useable to <100 µV [-38 dBu to + 45 dBu] ±0.1 dB + 100 µV (Vin >10 mV) ±0.05 dB (20 Hz-20 kHz) 20 Hz to 120 kHz Q=5 (2-pole) ±0.3 dB, 20 Hz-120 kHz 10 Hz to 100 kHz, THD+N mode .001 %-100 %	RMS response Peak respons Spurious Jitter Jitter & Ref Jitter On REFERENCE INF Input Formats Input Sample R Lock Range DIGITAL ANAI DIGITAL INPUT Input Formats Sample Rates Word Length EMBEDDED AUI Wideband Leve Range Frequency Range
Accuracy Resolution Phase Measurement Related Measurement Ranges Accuracy 20 Hz-20 kHz Resolution Level Meter Related (both cha Measurement Range Accuracy (1 kHz) Flatness (1 kHz ref) Bandpass Amplitude Function Tuning Range (f _o) Bandpass Response Accuracy (at f _o) THD+N / SINAD Function Fundamental Range Measurement Range SINAD Range Accuracy Measurement Bandwidth LF-3 dB	±2.0 deg 0.1 deq mnels) 10 mV to 140 V for specified accuracy and flatness, useable to <100 μV [-38 dBu to + 45 dBu] ±0.1 dB + 100 μV (Vin >10 mV) ±0.05 dB (20 Hz-20 kHz) 20 Hz to 120 kHz 20 Hz to 120 kHz 0=5 (2-pole) ±0.3 dB, 20 Hz-120 kHz 10 Hz to 100 kHz, THD+N mode .001 %-100 % 400 Hz-1 kHz ±1 dB, 20 Hz-120 kHz harmonics <10 or 400 Hz	RMS responss Peak respons Spurious Jitter & Ref Jitter & Ref Jitter On REFERENCE INF Input Formats Input Sample R Lock Range DIGITAL ANAI DIGITAL INPUT Input Formats Sample Rates Word Length EMBEDDED AUI Wideband Lever Range
Accuracy Resolution Phase Measurement Related Measurement Ranges Accuracy 20 Hz-20 kHz Resolution Level Meter Related (both cha Measurement Range Accuracy (1 kHz) Flatness (1 kHz ref) Bandpass Amplitude Function Tuning Range (f _o) Bandpass Response Accuracy (at f.) THD+N / SINAD Function Fundamental Range Measurement Range SINAD Range Accuracy Measurement Bandwidth LF-3 dB HF-3 dB Residual THD+N	±2.0 deg 0.1 deq mnels) 10 mV to 140 V for specified accuracy and flatness, useable to <100 µV [-38 dBu to + 45 dBu] ±0.1 dB + 100 µV (Vin >10 mV) ±0.05 dB (20 Hz-20 kHz) 20 Hz to 120 kHz Q=5 (2-pole) ±0.3 dB, 20 Hz-120 kHz 10 Hz to 100 kHz, THD+N mode .001 %-100 % 400 Hz-1 kHz ±1 dB, 20 Hz-120 kHz harmonics <10 or 400 Hz 22k, 30k, 80k, or 300 kHz	RMS responss Peak respons Spurious Jitter & Ref Jitter & Ref Jitter On REFERENCE INF Input Formats Input Sample R Lock Range DIGITAL ANAI DIGITAL INPUT Input Formats Sample Rates Word Length EMBEDDED AUI Wideband Leve Range Frequency Rang Accuracy Flatness High pass Filter
Accuracy Resolution Phase Measurement Related Measurement Ranges Accuracy 20 Hz-20 kHz Resolution Level Meter Related (both cha Measurement Range Accuracy (1 kHz) Flatness (1 kHz ref) Bandpass Amplitude Function Tuning Range (f _o) Bandpass Response Accuracy (at f _o) THD+N / SINAD Function Fundamental Range Measurement Range Measurement Range Measurement Bandwidth LF-3 dB HF-3 dB	±2.0 deg 0.1 deq mnels) 10 mV to 140 V for specified accuracy and flatness, useable to <100 μV [-38 dBu to + 45 dBu] ±0.1 dB + 100 μV (Vin >10 mV) ±0.05 dB (20 Hz-20 kHz) 20 Hz to 120 kHz 20 Hz to 120 kHz 0=5 (2-pole) ±0.3 dB, 20 Hz-120 kHz 10 Hz to 100 kHz, THD+N mode .001 %-100 % 400 Hz-1 kHz ±1 dB, 20 Hz-120 kHz harmonics <10 or 400 Hz	RMS responss Peak respons Spurious Jitter & Ref Jitter & Ref Jitter On REFERENCE INF Input Formats Input Sample R Lock Range DIGITAL ANAI DIGITAL INPUT Input Formats Sample Rates Word Length EMBEDDED AUI Wideband Leve Range Frequency Rang Accuracy Flatness High pass Filter Low pass Filter
Accuracy Resolution Phase Measurement Related Measurement Ranges Accuracy 20 Hz-20 kHz Resolution Level Meter Related (both cha Measurement Range Accuracy (1 kHz) Flatness (1 kHz ref) Bandpass Amplitude Function Tuning Range (f _o) Bandpass Response Accuracy (at f _o) THD+N / SINAD Function Fundamental Range Measurement Range Measurement Range Measurement Bandwidth LF - 3 dB HF - 3 dB Residual THD+N 25 Hz-20 kHz	±2.0 deg 0.1 deq nmels) 10 mV to 140 V for specified accuracy and flatness, useable to <100 μV [-38 dBu to + 45 dBu] ±0.1 dB + 100 μV (Vin >10 mV) ±0.05 dB (20 Hz-20 kHz) 20 Hz to 120 kHz 20 Hz to 120 kHz 2=5 (2-pole) ±0.3 dB, 20 Hz-120 kHz 10 Hz to 100 kHz, THD+N mode .001 %-100 % 400 Hz-1 kHz ±1 dB, 20 Hz-120 kHz hz	RMS responss Peak respons Spurious Jitter & Ref Jitter & Ref Jitter On REFERENCE INF Input Formats Input Sample R Lock Range DIGITAL ANAI DIGITAL INPUT Input Formats Sample Rates Word Length EMBEDDED AUI Wideband Leve Range Frequency Rang Accuracy Flatness High pass Filter
Accuracy Resolution Phase Measurement Related Measurement Ranges Accuracy 20 Hz-20 kHz Resolution Level Meter Related (both cha Measurement Range Accuracy (1 kHz) Flatness (1 kHz ref) Bandpass Amplitude Function Tuning Range (f _o) Bandpass Response Accuracy (at f,) THD+N / SINAD Function Fundamental Range Measurement Range SINAD Range Accuracy Measurement Bandwidth LF-3 dB HF-3 dB Residual THD+N	±2.0 deg 0.1 deq nmels) 10 mV to 140 V for specified accuracy and flatness, useable to <100 μV [-38 dBu to + 45 dBu] ±0.1 dB + 100 μV (Vin >10 mV) ±0.05 dB (20 Hz-20 kHz) 20 Hz to 120 kHz 20 Hz to 120 kHz 2=5 (2-pole) ±0.3 dB, 20 Hz-120 kHz 10 Hz to 100 kHz, THD+N mode .001 %-100 % 400 Hz-1 kHz ±1 dB, 20 Hz-120 kHz hz	RMS responss Peak respons Spurious Jitter & Ref Jitter & Ref Jitter On REFERENCE INF Input Formats Input Sample R Lock Range DIGITAL ANAI DIGITAL INPUT Input Formats Sample Rates Word Length EMBEDDED AUI Wideband Leve Range Frequency Rang Accuracy Flatness High pass Filter Low pass Filter

SMPTE (DIN) IMD Function	<u> </u>	
Test Signal Compatibility	40–250 Hz and 3 kHz–20 kHz in 0:1 to 8:1 ratio	
IMD Measured	Amplitude modulation products of	
Measurement Range	the HF tone. <0.0025 %-20 %	Narrow Band Amplitude
Accuracy	±1 dB per SMPTE RP-120-1983,	Frequency Range
Residual IMD	DIN 45403 ≤0.0025% [-92 dB], 60 + 7 kHz or	Filter Shape
Warre O. Flortton Franction	250 + 8 kHz	THD+N Measurements
Wow & Flutter Function Test Signal Compatibility	2.80 kHz-3.35 kHz	Fundamental Range
Accuracy (4 Hz)	±(5 % of reading + 0.002 %)	Residual THD+N
Detection Modes Residual W+F	IEC/DIN; NAB; JIS ≤0.005% Weighted; ≤0.01%	High pass Filters
Nesiduat W+I	Unweighted	Low pass Filters
DIGITAL SIGNAL GENERA	ATOR	Weighting Filters
DIGITAL OUTPUT CHARACTE		SMPTE (DIN) IMD Function
Output Formats	AES/EBU (per AES3-1992); SPDIF-	Test Signal Compatibility
Sample Rates	EIAJ; Optičal 28.8 kHz-99.9999 kHz	IMD Measured
Sample Rate Accuracy	±0.002% [±20 PPM] lockable to external reference	
Word Length	16 to 24 bits (even values)	Measurement Range Accuracy
Sine Wave		Residual IMD (0 dBFS)
Frequency Range	10 Hz to 47 % of sample rate (22.56 kHz at 48 ks/s)	Residuat IMD (0 dbl 3)
Frequency Resolution	Sample Rate ÷ 2 ²³	Frequency Measurements
Flatness	(typically 0.006 Hz at 48 ks/sec) ±0.001 dB	Range
Residual Distortion	±0.00001 % [-140 dB]	Phase Measurement Relate
Square Wave		Measurement Ranges Accuracy
Frequency Range Frequencies available	10 Hz to $1/6$ sample rate $f_s \div 4096$ to $f_s \div 6$, in even integer	Resolution
	divisors	BITTEST Measurement
SMPTE/DIN IMD Waveform		Measurement
Upper Tone Range Lower Tone Range	Choice of 7 kHz or 8 kHz Choice of 50 Hz, 60 Hz, 70 Hz, or 250 Hz	DIGITAL INTERFACE MEA
Amplitude Ratio	4:1 (LF:HF)	AES/EBU Impairments, Rea
Residual Distortion	≤0.00001 % [-140 dB] at 4:1 ratio	Input Sample Rate
Random Generator Waveform Waveform	Compatible with Audio Precision	Output to Input or Reference
wavelollii	BITTEST	Input to Input Delay
Dither (all waveforms)		
Probability Distribution	Triangular or rectangular; independent for each channel	AES/EBU Input Voltage Balanced
Spectral Distribution	Flat (white) or Shaped (+6 dB/oct,	
Amplitude	triangular only) Automatically tracks word length or off	Unbalanced
·		Jitter Amplitude (500 Hz)
AES/EBU INTERFACE GE Interface Signal	NERATION	Jitter Flatness
Amplitude Range		
Balanced (XĽR) Unbalanced (BNC)	0–5.11 Vpp, into 110 Ω in 5 mV steps 0–1.62 Vpp, into 75 Ω in 1.6 mV steps	Residual Jitter, peak calibrat
Channel Status Bits	English language decoded,	Spurious Jitter Products
Validity Flag	Professional/Consumer Selectable, set or cleared	Channel Status Bits
AES/EBU Impairments		
Induced Jitter	Sine wave	Validity Flag Parity; Signal Confidence;
Jitter Freq Range Jitter Amplitude	10 Hz to 38.8 kHz 0-1.28 UI (pk), in steps of 0.005 UI	Receiver Lock; Coding Error
oreter Ampticade	or better	AUXILIARY SIGNALS
	1.3–12.75 UI, in steps of 0.05 UI or better	Generator Analog Sync Outp
Residual Jitter RMS response	(total generator/analyzer) peak calibrated ≤0.005 UI (700 Hz-30 kHz BW) ≤0.015 UI (700 Hz-30 kHz BW)	Monitor; Analyzer Reading
Peak response	≤0.015 UI (700 Hz-30 kHz BW)	AUDIO MONITOR
Spurious Jitter Products Jitter & Ref Delay Off	≤0.0005 UI	Power Output
Jitter On	≤-30 dB below jitter signal	CENEDAL / ENVIDONMEN
Tabut Formats		GENERAL / ENVIRONMEN Power Requirements
Input Formats Input Sample Rates	AES/EBU (per AES3-1992) 28.8 kHz-99.9999 kHz	<u> </u>
Lock Range	±0.0025% [±25 PPM]	Temperature Range
DIGITAL ANALYZER		Humidity
DIGITAL INPUT CHARACTER	ISTICS	EMC
Input Formats	AES/EBU (per AES3-1992); SPDIF-	Dimensions
Sample Rates	EIAJ; Optical 28.8 kHz–99.9999 kHz	Difficusions
Word Length	16 to 24 bits	Weight Safety
EMBEDDED AUDIO MEASURI		Jaiety
Wideband Level/Amplitude		
Range Frequency Range	0 dBFS to -140 dBFS <10 Hz-22.0 kHz at 48 ks/sec	
Accuracy	±0.01 dB, ≥-90 dBFS	
Flatness High pass Filters	±0.01 dB, 15 Hz-22 kHz 22 Hz, 400 Hz, 2-pole Butterworth	Complete ATS-1 spe
Low pass Filters	15 kHz, 20 kHz 6-pole elliptic low-	from the Products
Weighting Filters	pass ANSI-IEC "A" weighting; CCIR QPK;	Web site at
	CCIR RMS	
Residual Noise	-140 dBFS unweighted; -142 dBFS	

-140 dBFS unweighted; -142 dBFS A-weighted

Frequency Range	0.04% to 40% of sample rate (10 Hz-19.2 kHz at 48.0 ks/sec)
Filter Shape	10-pole, Q=19 (BW = 5.3% of f _o)
THD+N Measurements	
Fundamental Range	0.02% to 45% of sample rate (10 Hz-22.0 kHz at 48.0 ks/sec
Residual THD+N	≤-138 dBFS
High pass Filters	22 Hz, 400 Hz 2-pole Butterworth
Low pass Filters	15 kHz, 20 kHz 6-pole elliptic low- pass
Weighting Filters	ANSI-IEC "A" weighting; CCIR QPK; CCIR RMS
SMPTE (DIN) IMD Function wi	th option "ATS-IMD"
Test Signal Compatibility	40-250 Hz and 3 kHz-20 kHz in 1:1 to 4:1 ratio
IMD Measured	Amplitude modulation products of the HF tone.
Measurement Range	<0.0001%-10%
Accuracy	±1 dB per SMPTE RP-120-1983, DIN 45403
Residual IMD (0 dBFS)	≤0.0001% [-120 dB], 60 + 7 kHz o 250 + 8 kHz
Frequency Measurements	
Range	5 Hz to 47% of sample rate
Phase Measurement Related	
Measurement Ranges	±180, +90/-270, or -90/+270 deg
Accuracy	±2.0 deg (20 Hz-20 kHz)
Resolution	0.1 deg
BITTEST Measurement	
Measurement	Compatible with random mode of Audio Precision BITTEST
DIGITAL INTERFACE MEAS	UREMENTS
AES/EBU Impairments, Real T	ime Displays
Input Sample Rate	±0.002% [±20 PPM] internal ref, ±0.0001% [*1 PPM] external ref
Output to Input or Reference Input to Input Delay	Measures status propagation from the AES/EBU output to the input. Range is 0–192 (frames), resolution ±60 ns.
AES/EBU Input Voltage Balanced	400 mV to 10.24 Vpp,
Unbalanced	±(10% + 50 mV) 100 mV to 2.56 Vpp, ±(10% + 30 mV)
Jitter Amplitude (500 Hz)	(peak-peak sine wave calibrated) 0-10 UI,
Jitter Flatness	±1.5 dB, 100 Hz-22 kHz (50 Hz HP selection, RMS detection, 48 kHz sample rate)
Residual Jitter, peak calibrated	BW)≤0.01 UÏ RMS; ≤0.03 UI Peak
Spurious Jitter Products	≤0.002 UI (1.2 kHz) or 0 dB below jitter signal
Channel Status Bits	English language decoded (Professional/Consumer)
Validity Flag	Displayed for selected channel
Parity; Signal Confidence;	Displayed for total signal (both
Receiver Lock; Coding Error	channels combined)

AUXILIARY SIGNALS

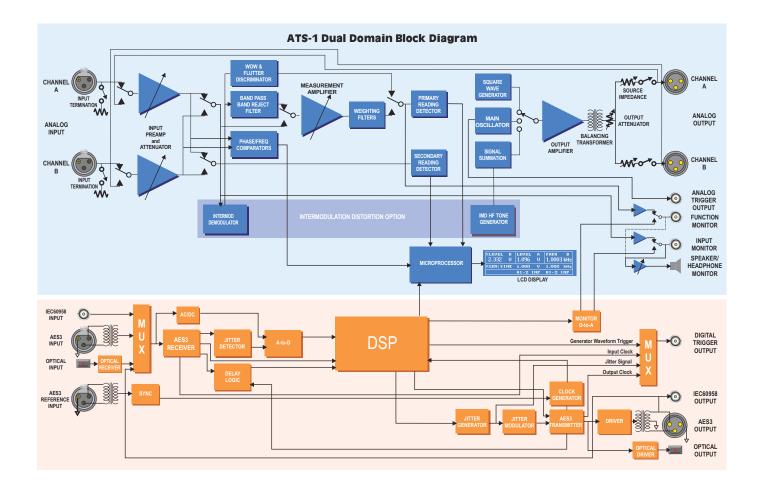
Generator Analog Sync Output; Digital Sync Output; Analyzer Input Monitor; Analyzer Reading

AUDIO MONITOR
Power Output

Typically 1 watt

GENERAL / ENVIRONMENTAL	
Power Requirements	100/120/230/240 Vac (-10%/+6%), 50-60 Hz, 50 VA max
Temperature Range	0° C to +50° C Operating; -20° C to +60° C Storage
Humidity	90% RH to at least +40° C (non- condensing)
EMC	Complies with 89/336/EEC, CISPR 22 (class B), and FCC 15 subpart J (class B)
Dimensions	16.5 x 6.0 x 13.6 inches [41.9 x 15.2 x 34.5 cm]
Weight	Approximately 20 lbs [9.1 kg]
Safety	Complies with 73/23/EEC, 93/68/EEC, EN61010, and IEC 1010 (including Amendments 1 and 2)

Complete ATS-1 specifications are downloadable from the Products area of the Audio Precision Web site at audioprecision.com.



Ordering Informa		
ATS-1A	ATS-1 Access Audio Test System with GPIB interface	
ATS-1DD	ATS-1 Dual Domain (digital and analog) Audio Test System with GPIB interface	
	Select panel type and front or rear connections at time of order:	
	ATS-BNC: BNC and banana jack connector panel ATS-XLR: XLR and banana jack connector panel ATS-PHJ: ¼-inch phone and banana jack connector panel	
	ATS-R: Rear mount (front mount connector panel is default)	
Options and Acc	cessories for ATS-1 Instruments	
ATS-IMD	$\label{lem:smpte} SMPTE/DIN\ intermodulation\ distortion\ measurement\ and\ generation\ (analog\ and\ digital)$	
RAK-ATS	Rack mount shelf for ATS-1 Access or ATS-1 Dual Domain	
MAN-ATSA	Additional ATS-1 Access operator's manual (one included with instrument)	
MAN-ATSDD	Additional ATS-1 Dual Domain operator's manual (one included with instrument)	
MAN-ATS488	Additional GPIB manual for ATS-1 Access or ATS-1 Dual Domain (one included with instrument)	
SVC-ATS	Service manual for ATS-1 Access or ATS-1 Dual Domain	
CAB-XMF	Set of four XLR male to XLR female cables	
CAB-XBR	Set of four XLR male/female to RCA/BNC cables	
CAB-AES	Set of two AES3 digital cables, 1 meter	
CAB-AES2	Set of two AES3 digital cables, 2 meters	
CAB-AES4	Set of two AES3 digital cables, 4 meters	

ATS-1 includes a removable carrying handle. Portable and self-contained, take your ATS-1 with you on the road.

BUYING AN ATS-1 ANALYZER FOR ANALOG AND DIGITAL AUDIO:

What to look for when evaluating competitive instruments

Digital Architecture and Features: Not all analyzers that accept a digital input signal are actually digital analyzers. Does the instrument have a real (DSP-implemented) digital domain analyzer, or just a D/A converter from the digital input connector to an analog hardware analyzer? This latter approach in a competitive unit yields distortion performance in the 12-14 bit range (-70 to -85 dB THD+N, for example). There's just not that much 12-bit digital audio around to measure anymore. ATS-1 Dual Domain's digital analyzer guarantees -130 dB residual distortion (nearly 22 bit performance), far in excess of the -108 to -112 dB actual linearity of today's best A/D converters.

Analog Performance: Does the instrument have an analog hardware generator and an analog hardware analyzer? Some competitive units (at twice the price of ATS-1 Dual Domain) use DSP techniques for all generation and analysis, so analog signals pass

16.15

through converters inside the instrument. The result is THD+N as high as -79 dB, flatness as poor as -0.2 dB—inadequate for most modern audio devices.

Interface Testing: Does the instrument have independent analog, digital, and jitter generators? If it can only provide analog or digital output at any one time, you can't test a house-synchronized A/D converter for jitter rejection. Without independent, flexible digital audio and jitter generators, you can't measure jitter sensitivity of a D/A converter at various audio and jitter frequency combinations.

True Dual Domain: True Dual Domain hardware by definition guarantees a full range of analysis capabilities in both analog and digital domains. Everyone measures level and some measure THD+N (although implemented with extremely limited performance, as noted above). Be sure that other useful measurements such as IMD (Intermodulation Distortion), Phase, and Crosstalk are available for both analog and digital signals, not just analog.



Testing for Optimal Results
5750 SW Arctic Drive
Beaverton, Oregon 97005
Tel 503-627-0832 Fax 503-641-8906
US Toll Free 1-800-231-7350
email: sales@audioprecision.com
web: audioprecision.com